

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application Serial No. ....10/632,273  
Filing Date ..... July 31, 2003  
Inventor ..... Warren M. Farnworth et al.  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2829  
Examiner ..... Russell M. Kobert  
Attorney's Docket No. ....MI22-2379  
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and  
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: \_\_\_\_\_

\_\_\_\_\_  
D. Brent Kenady  
Reg. No. 40,045  
Customer No. 021567

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
**MI22-2379**SERIAL NO.  
**10/632,273**LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
**Warren M. Farnworth**FILING DATE  
**July 31, 2003**GROUP  
**2829**

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AL						
	AI <sup>2</sup>						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	<b>3-69131</b>	<b>8/1998</b>	<b>Japan</b>			<b>X</b>	
	AN							
	AO							
	AP							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.